

**Search Notes**

Application/Control No.

10/820,315

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

GREBENNIKOV ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	285	3/1/2006	HN
330	296	3/1/2006	HN
330	133	3/1/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	3/1/2006	HN
EAST UPDATE SEARCH SEE PRINT OUT	3/1/2006	HN